## Notice of References Cited Application/Control No. 10/720,923 Examiner Huy Q. Phan Applicant(s)/Patent Under Reexamination BUSHNELL ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0025047 A1	02-2004	Mayne et al.	713/200
*	В	US-2004/0009749 A1	01-2004	Arazi et al.	455/41.2
*	С	US-2003/0139180 A1	07-2003	McIntosh et al.	455/426
*	D	US-5,890,055 A	03-1999	Chu et al.	455/16
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2406015 A	03-2005	United Kingdom	DOCHERTY et al.	H04M 01/60
	0					
	Р					•
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
U							
V							
w							
x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.